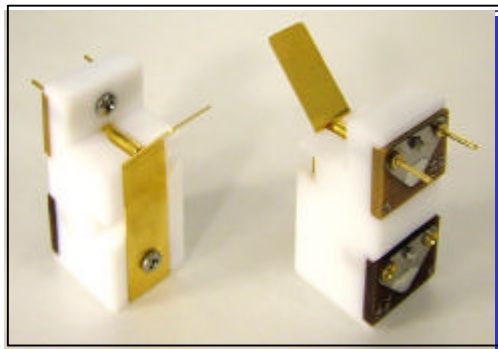




W-2500 COMPONENT TEMPERATURE TEST SYSTEM

- Automated, software driven component temperature test system
- System can be configured for capacitor, inductor, resistor, diode or transistor testing
- Typical testing applications are sampling test, final Q.C. test and new component evaluation
- Open, short and load calibration, isolated carriers, Kelvin contacts and shielded cables for accurate measurements
- Test wheels accommodate axial, radial, chip capacitors and many other special geometry type devices



Teflon-Isolated Chip Carrier

- Selectable test parameters with user defined Q.C. limits including sorting and grouping features
- All data published in a *Microsoft Access*™ data base and can be exported to *Microsoft Excel*™ for custom data analysis
- Printouts are generated using *Crystal Reports*®
- Sharing of test results via network

SPECIFICATIONS

Temperature Range: -55° C to 150° C
Temperature Stability: ± 0.1° C

SAUNDERS & ASSOCIATES, LLC

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SYSTEM CONFIGURATION

- S&A 4220 Temperature Test Chamber (CO2, LN2, or Mechanical Refrigeration)
- Measurement Option (listed below)
 - Computer with *Windows XP*®
 - System Software

MEASUREMENT OPTIONS

- **Capacitor / Inductor Test System**
 - Measurement Equipment: LCR Bridge, High Voltage Power Supply
 - Example Measurements: C, D, Q, L, CTC, LTC, C@V, L@V
- **Insulation Resistance Test System**
 - Measurement Equipment: Picoammeter, High Voltage Power Supply
 - Example Measurements: I, IR
- **Resistor Test System**
 - Measurement Equipment: Digital Multimeter
 - Example Measurements: R, RTC
- **Diode Test System**
 - Measurement Equipment: Source Meter, 2473 Multiplexer
 - Example Measurements: VF, VR, VB, IF, IR, IP
- **Transistor Test System**
 - Measurement Equipment: Lorlin or FEC Interfaces
 - Example Measurement: Bin Number
- **Combination and custom systems available**

SAMPLE REPORTS

The screenshots display various data points and graphs from a test system. One table shows component data with columns for ID, Frequency, Capacitance, Dissipation Factor, and Temperature. Another graph shows the relationship between capacitance and temperature for a specific component.

ID	Freq (MHz)	Cap (pF)	D	Temp (°C)
8081	9.1578	10.7	-8.002415	-78.7
8081	9.1578	10.7	8.002415	115.03
8081	9.1578	10.7	8.002457	-78.7
8081	9.1578	10.7	8.002457	115.03

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